

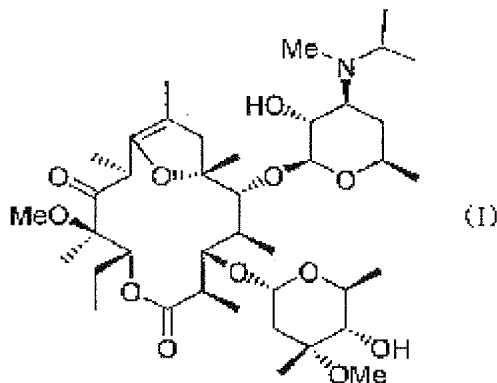
Amendments to the Claims

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

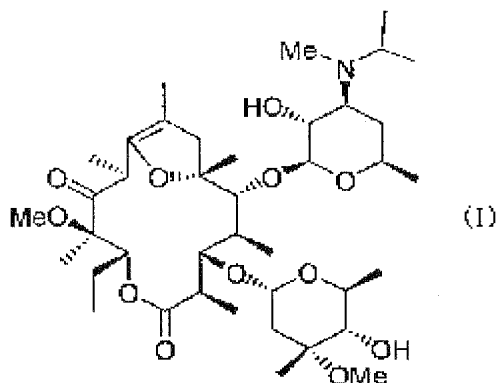
Claims 1-7. (Cancelled)

8. (Original) A hemifumarate crystal of a compound of formula (I):



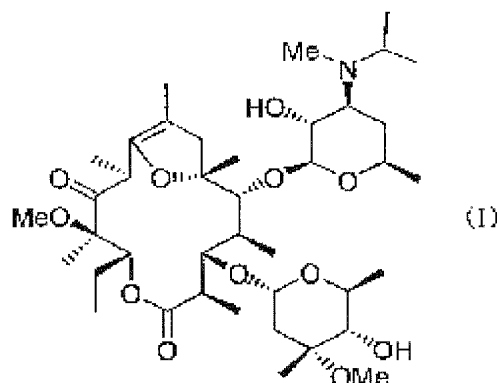
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°.

9. (Original) A hemifumarate crystal of a compound of formula (I):



containing acetone and showing strong X-ray diffraction peaks at diffraction angles $2\theta = 5.4^\circ$, 10.4° , 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

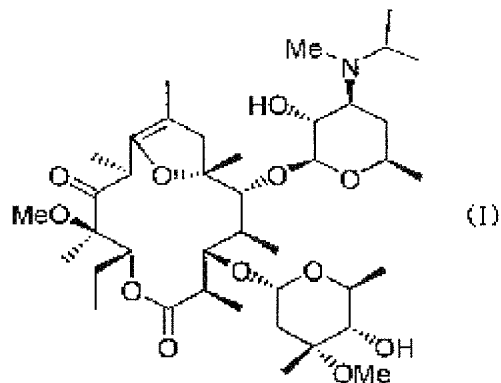
10. (Previously Presented) A hemifumarate crystal of a compound of formula (I):



containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles $2\theta = 5.4^\circ$, 10.4° , 10.7° and 12.1° measured by X-ray

diffractometry using Cu-K α radiation.

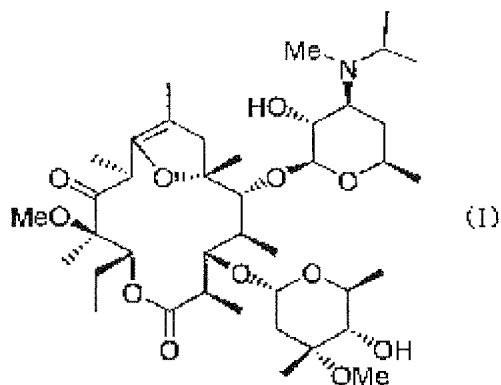
11. (Original) A hemifumarate crystal of a compound of formula (I):



containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

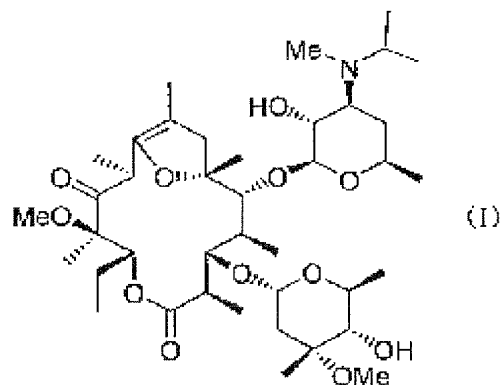
Claims 12-15. (Cancelled)

16. (Previously Presented) A process for preparing a hemifumarate anhydrate of a compound of formula (I):



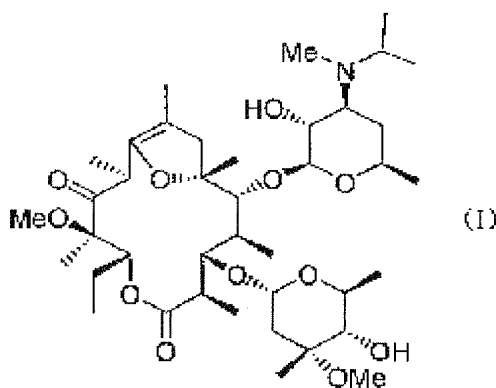
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of obtaining said anhydrate by drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

17. (Previously Presented) A process for preparing a hemifumarate hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of showing strong X-ray diffraction peaks at diffraction angles $2\theta = 7.1^\circ$ and 14.2° , said process comprising the step of obtaining said hydrate by drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

18. (Previously Presented) A process for preparing a hemifumarate hydrate of a compound of formula (I):

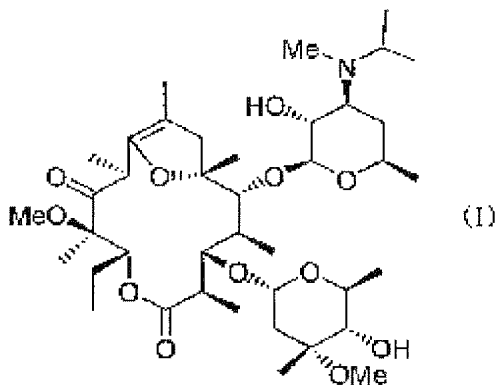


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , said process comprising the step of conditioning a hemifumarate anhydrate of the compound of formula

(I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , wherein said anhydrate is obtained by drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

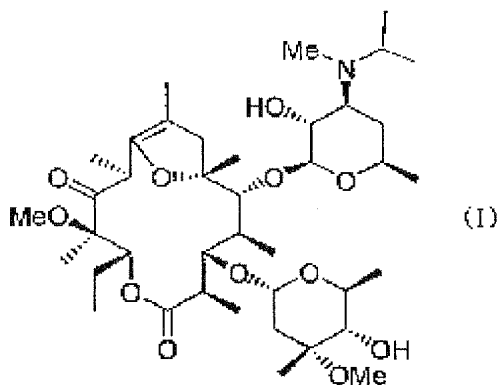
Claims 19-24. (Cancelled)

25. (Previously Presented) A process for preparing a hemifumarate anhydrate of a compound of formula (I):



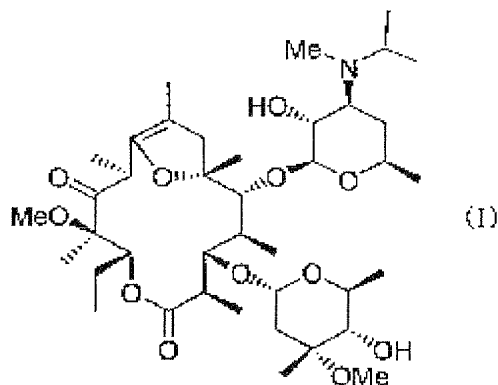
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , said process comprising treating Crystal form C at $20-40^{\circ}\text{C}$ in a mixed solvent of ethyl acetate and water to obtain Crystal Form E, and stirring the

Crystal Form E in a mixed solvent of ethyl acetate and water at less than 20°C to obtain a hemifumarate crystal of a compound of formula (I):



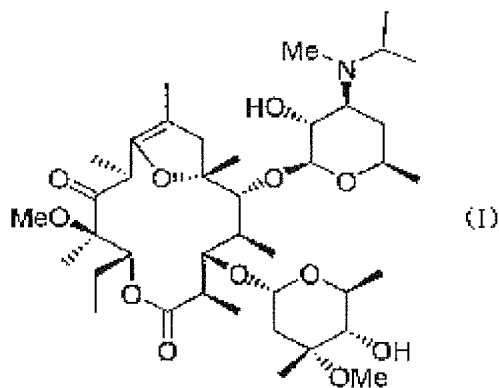
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, and drying the hemifumarate crystal under reduced pressure to obtain said anhydrate.

26. (Previously Presented) A hemifumarate anhydrate of a compound of formula (I):

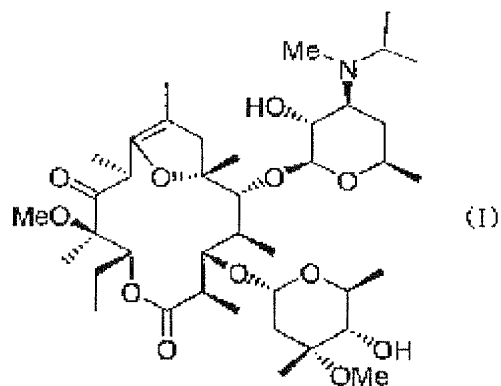


Characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.15° and 14.2° , which crystal is obtained by the process of claim 25.

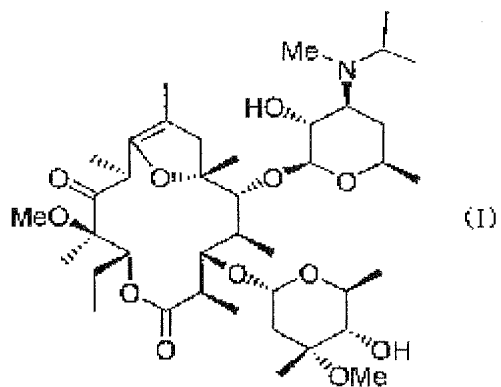
27. (Currently Amended) A process for preparing a hemifumarate hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , said process comprising stirring Crystal Form E in a mixed solvent of ethyl acetate and water to obtain a hemifumarate crystal of a compound of formula (I):



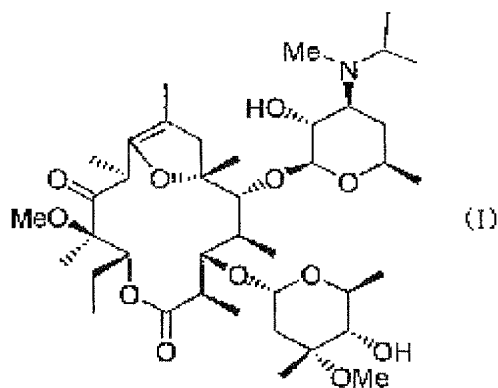
Characterized by 2-theta angle positions in the powder X-ray diffraction patterns of 6.6° and 8.5°, and drying the hemifumarate crystal under reduced pressure to obtain a hemifumarate anhydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, and conditioning the anhydrate to obtain said hydrate;

wherein crystal Form E is a hemifumarate hydrate of a compound of formula (I) that contains tetrahydrofuran and that has 2-theta angle positions in the powder X-ray diffraction pattern of 5.6° and 10.4° as measured X-ray diffractometry.

28. (Previously Presented) A hemifumarate hydrate of a compound of formula (I):

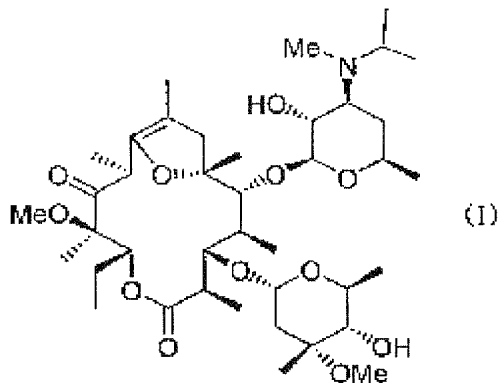


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, which crystal is obtained by the process of claim 27.

Claims 29-34. (Cancelled)

35. (Currently Amended) Crystal form D of a

hemifumarate hydrate of a compound of formula ~~(I)~~ (I):



which crystal is obtained via Crystal Form E.